

<b>Form 1449 (Modified)</b>  <b>Information Disclosure Statement By Applicant</b>  (Use Several Sheets if Necessary)	Atty. Docket No. HIT1P022/ HSJ9-2003-0129US1	Application No.: Unassigned 10/672,896
	Applicant: Quang Le et al.	Group Art Unit: Unassigned 3729
	Filing Date: Herewith	

**U.S. Patent Documents**

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
TN	A	2003/0021063	01/30/2003	Kuroda et al.	360	125	02/19/2002
TN	B	2002/0078553	06/27/2002	Sato	29	603.15	12/18/2001
TN	C	2002/0026704	03/07/2002	Stageberg et al.	29	603.12	08/13/2001
TN	D	6,556,377	04/29/2003	Chen et al.	360	126	09/06/2002
TN	E	5,658,470	08/19/1997	Schultz et al.	216	22	12/13/1995
TN	F	4,943,882	07/24/1990	Wada et al.	360	126	12/23/1988
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**Foreign Patent or Published Foreign Patent Application**

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
TN	M	7225912	1995-08-22	JP	G11B	5/187		
TN	N	3241511	1991-10-28	JP	G11B	5/31		
TN	O	3235210	1991-10-21	JP	G11B	5/31		
TN	P	1048217	1989-02-22	JP	G11B	5/31		
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TN	R	63098815	1988-04-30	JP	G11B	5/31		
TN	S	63029311	1988-02-08	JP	G11B	5/31		
TN	T	61115212	1986-06-02	JP	G11B	5/31		
TN	U	3100911	1991-04-25	JP	G11B	5/31		
TN	V	62262213	1987-11-14	JP	G11B	5/31		
TN	W	61057016	1986-03-22	JP	G11B	5/127		

**Other Documents**

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
TN	U	Bai, Daniel et al., "Stitched Pole-Tip design with enhanced head field for perpendicular recording", Journal of Applied Physics, Volume 93, Number 10, May 15, 2003
TN	V	Yamakawa, Kiyoshi, "Writing performance of narrow trackwidth single pole perpendicular heads", Journal of Applied Physics, Volume 87, Number 9, May 1, 2000
Examiner /Tai Nguyen/		Date Considered 06/08/2006

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	<b>Applicant:</b> Quang Le et al.	
	<b>Filing Date:</b> 09/26/2003	<b>Group Art Unit:</b> 3729

**U.S. Patent Documents**

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
TN	A	6,513,228	02/04/2003	Khizroev et al.	29	603.14	09/21/2000
	B						
	C						
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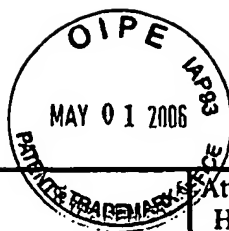
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							Yes	No
	L							
	M							
	N							
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	P							

**Other Documents**

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	R	
	S	
	T	
Examiner	/Tai Nguyen/	Date Considered 06/08/2006

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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#### U.S. Patent Documents

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							Yes	No
	L							
	M							
	N							
	O							
	P							

#### Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
TN	R	Yamakawa et al., "Highly Sensitive Single-Pole thin Film Head" IEEE Translation Journal on Magnetics In Japan, Vol. 4, No. 2, Feb. 1989
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Examiner /Tai Nguyen/	Date Considered 06/08/2006
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06/08/06

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.